

Date
Test by : E.V.
Specification : AL-SL-DL-CC-IP68-24-RGB-32
Sample No. : 1

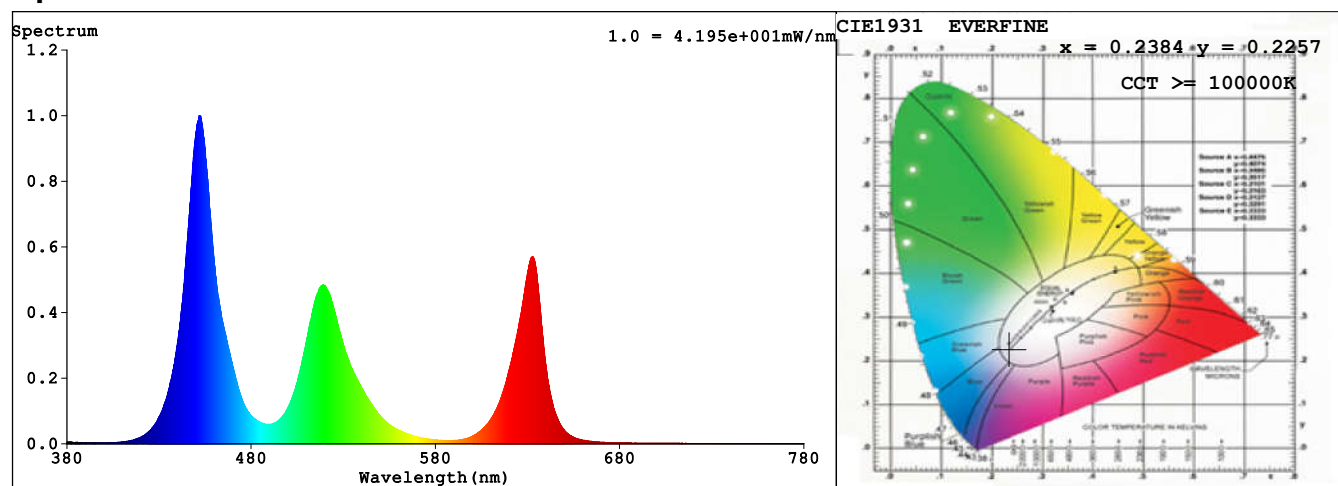
Sam. Status : First Sample Test
Instrument : HaasSuite(EVERFINE)
Remark : 1M
Device SN : HS-2000

Test Condition

Temperature : 25Deg
WL Range : 380nm-780nm
Test Mode : Fast Test
Sensitivity : High

RH : 60.0%
IP : 51670 (79%)
T : 174 ms

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: $x = 0.2384$ $y = 0.2257$ / $u' = 0.1823$ $v' = 0.3883$ ($duv = -8.23e-03$)

CCT>=100000K Prcp WL: $L_d = 474.3\text{nm}$ Purity=42.8%

Peak WL: $L_p = 452\text{nm}$ FWHM: $\approx 17.3\text{nm}$ Ratio: R=20.3% G=71.1% B=8.6%

Render Index: $R_a = 53.7$ CRI = 47.8 TM30: $R_f = 57$ $R_g = 127$

EEL: 0.26417 B

R1=40 R2=82 R3=65 R4=37 R5=58 R6=79 R7=65

R8=4 R9=0 R10=58 R11=12 R12=73 R13=49 R14=76 R15=19

LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 450.45 lm Eff.: 41.85 lm/W $\Phi_e = 2.1059\text{ W}$

Electrical parameters

V = 24.10 V I = 0.4467 A P = 10.76 W PF = 1.000 F=0.00 Hz

 EVERFINE

Date
Test by : E.V.
Specification : AL-SL-DL-CC-IP68-24-RGB-32
Sample No. : 2

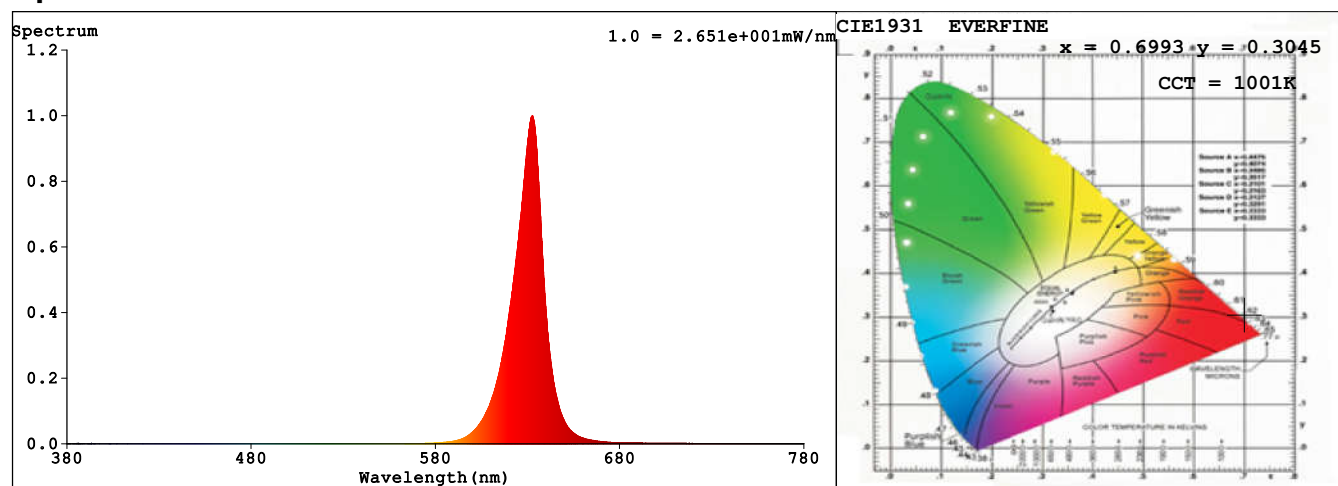
Sam. Status : First Sample Test
Instrument : HaasSuite(EVERFINE)
Remark : 1M
Device SN : HS-2000

Test Condition

Temperature : 25Deg
WL Range : 380nm-780nm
Test Mode : Fast Test
Sensitivity : High

RH : 60.0%
IP : 57210 (87%)
T : 174 ms

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: $x = 0.6993$ $y = 0.3045$ / $u' = 0.5322$ $v' = 0.5215$ ($duv = -8.37e-02$)
CCT= 1001K Prcp WL: Ld=621.8nm Purity=100.0%
Peak WL: Lp=633nm FWHM: =16.5nm Ratio:R=96.9% G=3.1% B=0.0%
Render Index: Ra = 25.9 CRI = 29.8 TM30:Rf=0 Rg=0

EEL: 0.24010 B

R1=6 R2=78 R3=30 R4=0 R5=0 R6=90 R7=4
R8=0 R9=0 R10=72 R11=0 R12=79 R13=29 R14=59 R15=0
LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 103.82 lm Eff.: 30.77 lm/W Fe = 540.11 mW

Electrical parameters

V = 24.00 V I = 0.1406 A P = 3.374 W PF = 1.000 F=0.00 Hz

 EVERFINE

Date
Test by : E.V.
Specification : AL-SL-DL-CC-IP68-24-RGB-32
Sample No. : 3

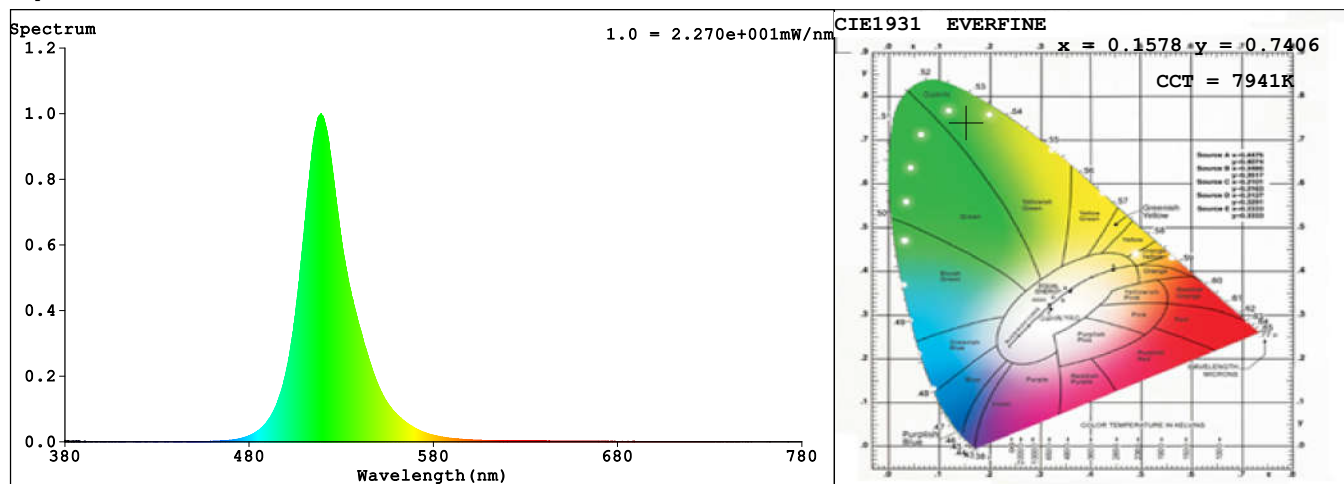
Sam. Status : First Sample Test
Instrument : HaasSuite(EVERFINE)
Remark : 1M
Device SN : HS-2000

Test Condition

Temperature : 25Deg
WL Range : 380nm-780nm
Test Mode : Fast Test
Sensitivity : High

RH : 60.0%
IP : 53767 (82%)
T : 208 ms

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: $x = 0.1578$ $y = 0.7406$ / $u' = 0.0546$ $v' = 0.5760$ ($duv=1.63e-01$)

CCT= 7941K Prcp WL: Ld=526.0nm Purity=83.2%

Peak WL: Lp=519nm FWHM: =26.2nm Ratio:R=0.3% G=98.1% B=1.6%

Render Index: Ra = 0.0 CRI = 2.2 TM30:Rf=1 Rg=6

EEL: 0.09825 A++ Highest

R1=0 R2=0 R3=0 R4=0 R5=0 R6=0 R7=0
R8=0 R9=0 R10=0 R11=0 R12=0 R13=0 R14=34 R15=0
LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 358.05 lm Eff.: 106.57 lm/W Fe = 742.67 mW

Electrical parameters

V = 24.00 V I = 0.1400 A P = 3.360 W PF = 1.000 F=0.00 Hz

 EVERFINE

Date
Test by : E.V.
Specification : AL-SL-DL-CC-IP68-24-RGB-32
Sample No. : 4

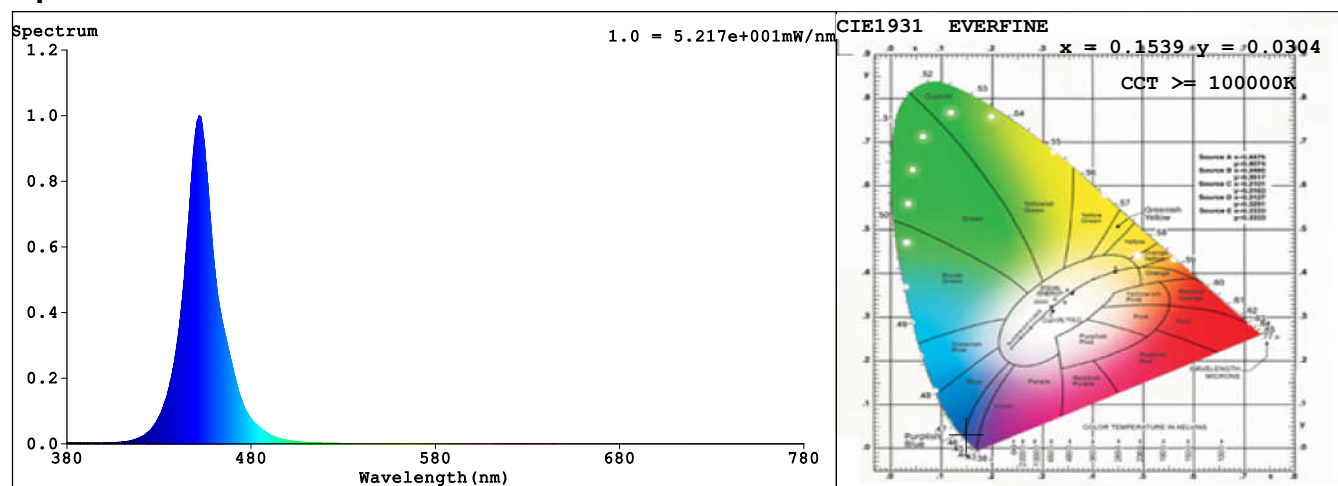
Sam. Status : First Sample Test
Instrument : HaasSuite(EVERFINE)
Remark : 1M
Device SN : HS-2000

Test Condition

Temperature : 25Deg
WL Range : 380nm-780nm
Test Mode : Fast Test
Sensitivity : High

RH : 60.0%
IP : 53489 (82%)
T : 166 ms

Spectrum



Colorimetric Parameters

Chromaticity Coordinate: $x = 0.1539$ $y = 0.0304$ / $u' = 0.2013$ $v' = 0.0896$ ($duv = -2.10e-01$)
CCT>=100000K Prcp WL: Ld=455.8nm Purity=97.8%
Peak WL: Lp=452nm FWHM: =17.3nm Ratio:R=0.7% G=8.3% B=91.0%
Render Index: Ra = 0.4 CRI = 0.4 TM30:Rf=0 Rg=14

EEL: 0.41179 B

R1=0 R2=0 R3=0 R4=0 R5=3 R6=0 R7=0
R8=0 R9=0 R10=0 R11=0 R12=0 R13=0 R14=0 R15=3
LEVEL:OUT WHITE:OUT

Photometric & Radiometric Parameters

Flux = 45.596 lm Eff.: 13.54 lm/W Fe = 1.1914 W

Electrical parameters

V = 24.00 V I = 0.1403 A P = 3.367 W PF = 1.000 F=0.00 Hz

